

LECTRONICS TESTING CENTER, TAIW

Report No.: 11-01-MAS-055-03

EMC TESTING DEPARTMENT

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TEST REPORT **FOR** IEC 61643-1 (7.5.3) (SURGE IMMUNITY TEST)

Report No.: 11-01-MAS-055-03

Client:

JD Auspice Co., Ltd.

Product:

DC Surge Protectetive Device

Model No .:

PV40/***-MVCR

Comment Issues:

N/A

Manufacturer/supplier:

JD Auspice Co., Ltd.

Serial Voltage

500Vdc / 600Vdc

Date test item received:

2011/01/07

Date test campaign completed:

2011/02/09

Date of issue

2011/02/09

The test result only corresponds to the tested sample. It is not permitted to copy this report, in part or in full, without the permission of the test laboratory.

Total number of pages of this test report: 10 pages

Test Engineer

Checked By

Yi-hone Cheng

Kevin Lin

ELECTRONICS TESTING CENTER, TAIWAN NO.8, LANE 29, WEN-MING RD., LO-SHAN TSUN, KUI-SHAN HSIANG, **TAOYUAN HSIEN 33383**

TAIWAN, R.O.C.

TEL: (03) 3276170~4 INT: +886-3-3276170~4 FAX: (03) 3276188

INT: +886-3-3276188

Laboratory Introduction: Electronics Testing Center, Taiwan is recognized, filed and mutual recognition arrangement as following:

ISO9001: TüV Product Service

2 ISO/IEC 17025: BSMI, CNLA, DGT, NVLAP, CCIBLAC, UL, Compliance

3 Filing: FCC, Industry Canada, VCCI

MRA: Australia, Hong Kong, New Zealand, Singapore, USA, Japan, Korea, China, APLAC through CNLA

© FCC Registration Number: 90588, 91094, 91095

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SURGE IMMUNITY TEST

Test Date: Jan. 21, 2011

Test Specification	IEC61643-1 (7.5.3)				
Test Equipment					
Lightning Surge Simulator \ Noiseken \ LSS-15AX Voltage Probe \ Tektronix \ P6015A Oscilloscope \ Tektronix \ TDS784A					
Climatic Condition	Ambient Temperature: <u>15</u> °C Rel		Relative Humidity: <u>65</u> %RH		
	Atmospheric Pressure: 993 mbar				
Test Set-up	Table-top Equipment				
Operating Conditions of The Device		Static Mode			

Waveform: 1.2/50 μ s(8/20 μ s)		Repetition rate: <u>60</u> sec	Times: 5 times/each condition	
\Mode \Voltage \Polarity \Result		Surge HOT: Device Input	Surge COM: Device Output	
6.0 kV	+	A		
	-	A		
0.9kV ~ 15.0 kV Step:10% increase	+	A		
	-	A		

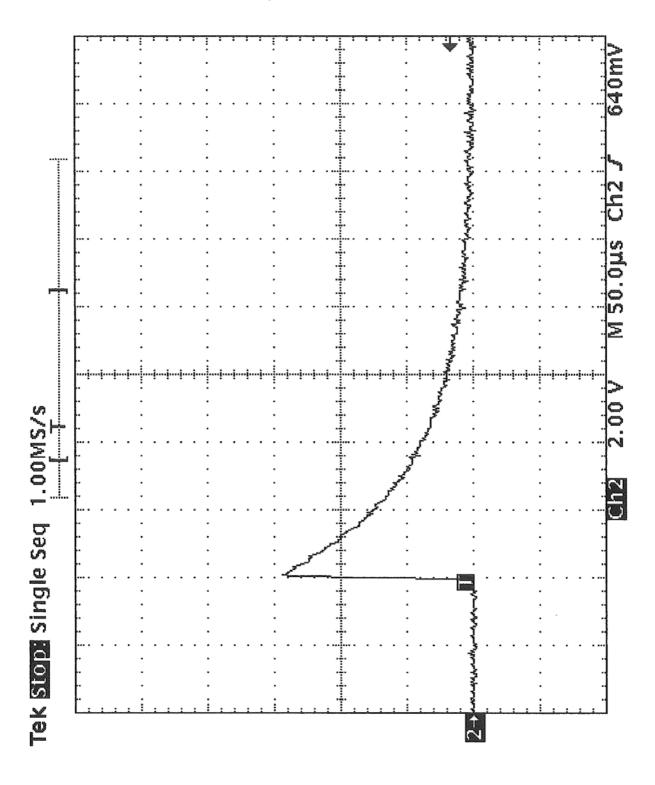
Note: "A" means the EUT function was correct during the test.



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C2 Max 5.76 V C2 Min -160mV

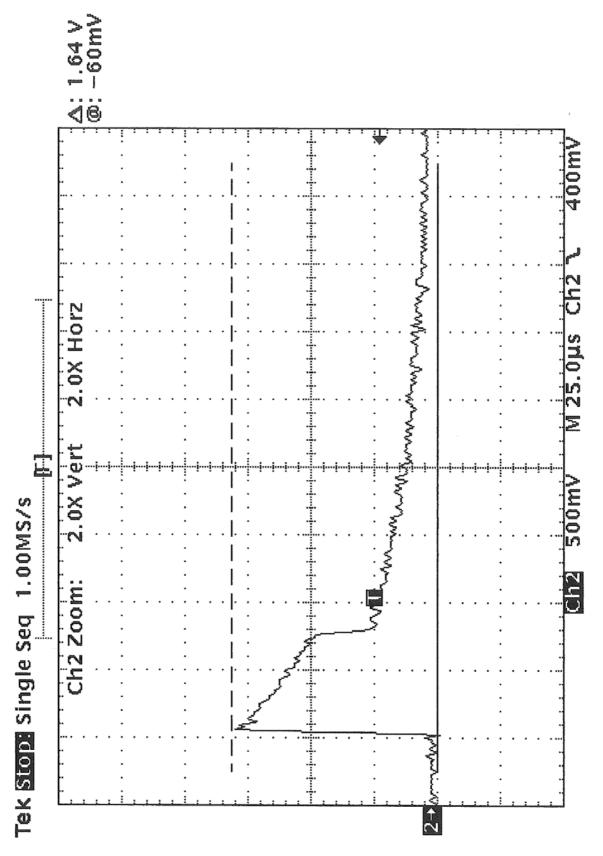




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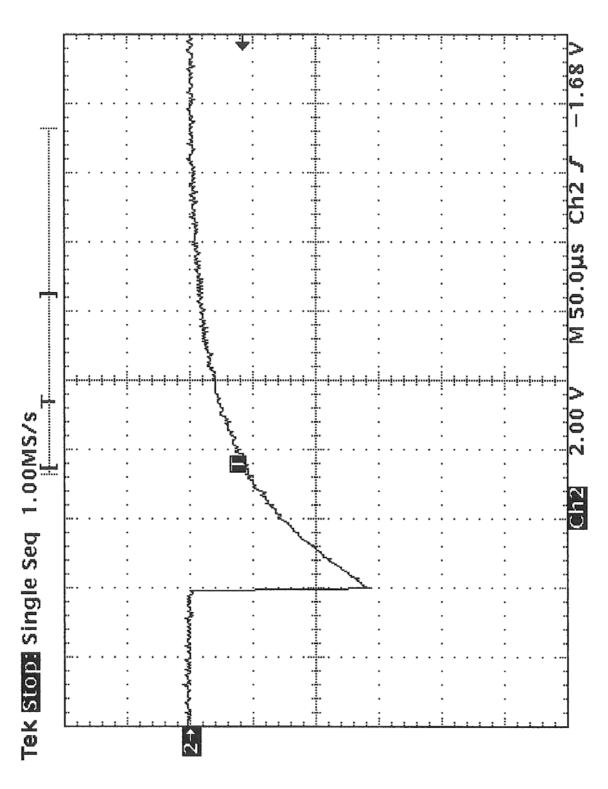




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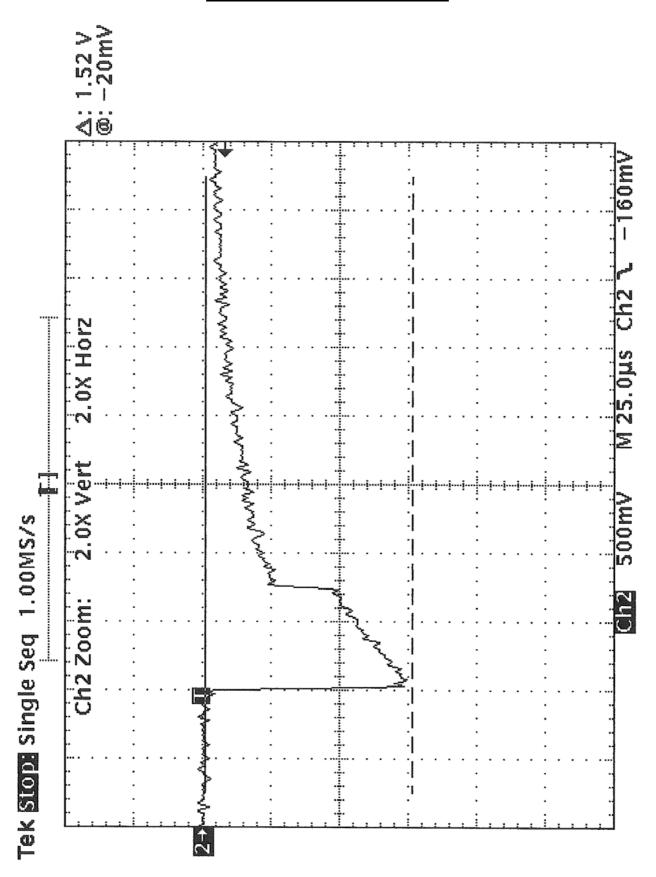






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Test Voltage: -6kV (Device Parallel)

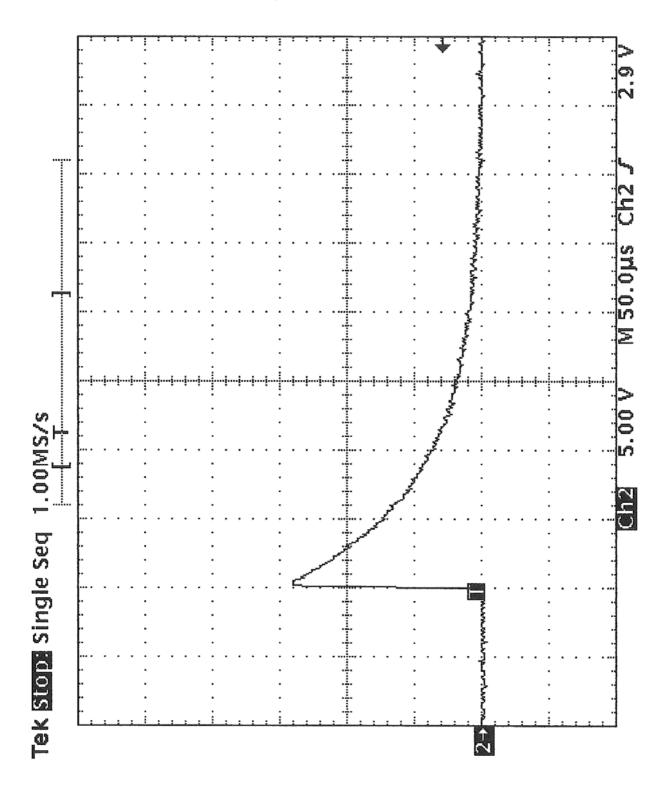




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Test Voltage: +15.0 kV Waveform (Normal)

C2 Max 14.1 V C2 Min

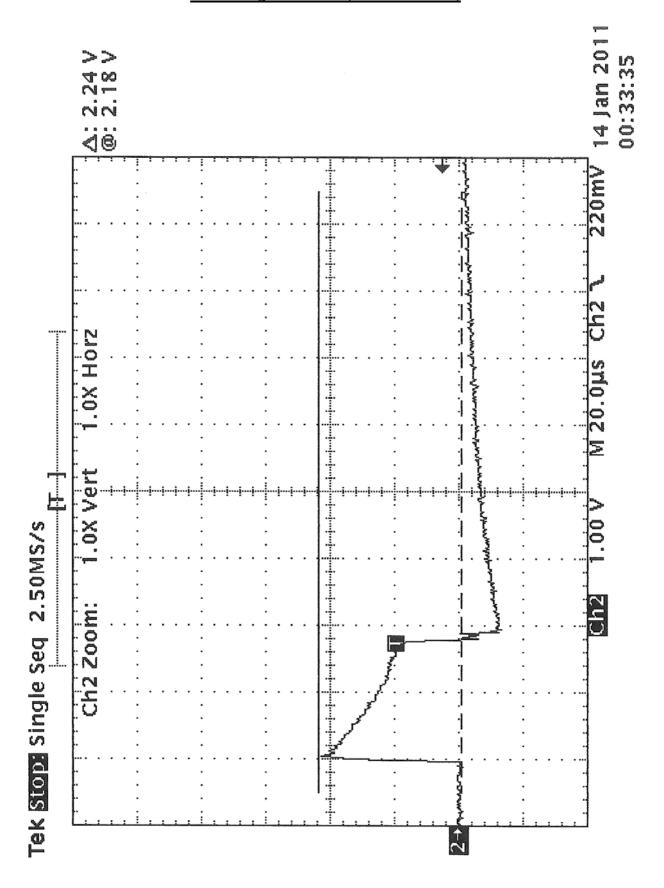




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Test Voltage: +15.0 kV (Device Parallel)



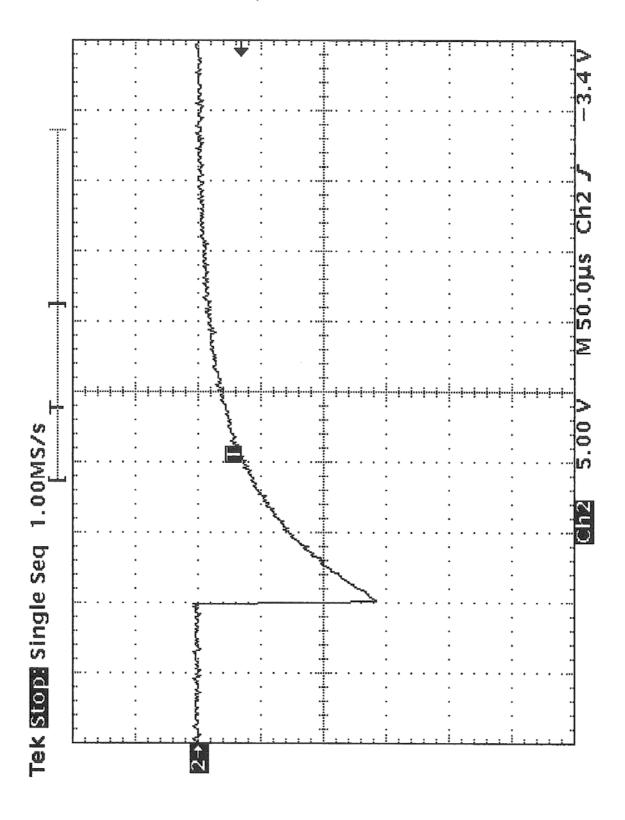


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C2 Max 400mV C2 Min -14.2 V



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Test Voltage: -15.0 kV (Device Parallel)

